Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | STASZEWSKI ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0034260 A1	03-2002	Kim, Wang Rae	375/296
*	В	US-6,373,902 B1	04-2002	Park et al.	375/296
*	С	US-2002/0080891 A1	06-2002	Ahn et al.	375/297
*	D	US-6,549,067 B1	04-2003	Kenington, Peter	330/52
*	Ε	US-2003/0083724 A1	05-2003	Jog et al.	607/122
*	F	US-6,711,388 B1	03-2004	Neitiniemi, Jukka-Pekka	455/127.1
*	G	US-6,724,255 B2	04-2004	Kee et al.	330/251
	н	US-			
	ı	US-			
	J	US-		·	
	К	US-			
i i	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р			·		·
	Q				•	·
	R					
	s					
	Т				·	

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.